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PATENT NUMBER and ISSUE DATE

U.S. UTILITY Patent Application

APPL NUM 10042060	FILING DATE 01/07/2002	CLASS 117	SUBCLASS	GAU 1765	EXAMINER ANDERSON		
**APPLICANT	S: Kuhn H:	arald; Ste	in Rene; Voel	kl Johan	A STATE OF THE PARTY OF THE PAR		
**CONTINUING DATA VERIFIED: THIS APPLICATION IS A CON OF PCT/DE00/02174 07/04/2000							
** FOREIGN APPLICATIONS VERIFIED: 10 79/5 37 333.4 07/07/1999							
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Foreign priority clair 35 USC 119 conditi		ع yes تع√yeş			ATTORNEY DOCKET NO		
Verified and Acknow	wledged Examiners's in	tials ///	L .		GR99P3456		
FITLE: Method for the sublimation growth of an SiC single crystal, involving heating under growth pressure							
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NOTICE OF ALLOWANCE MAILED			CLAIMS ALLOWED				
		Assistant Examiner	Total Claims		Print Claim for O.G		
ISSUE FEE		•	 	DRAWING			
Amount Due	Date Paid		Sheets Drwg.	Figs.Drwg.	Print Fig.		
		Primary Examiner		l	1		
TERMINAL		PREPARED FOR ISSUE	Application Examiner				
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